

**Features**

- **Fast Read Access Time - 150 ns**
- **Automatic Page Write Operation**  
Internal Address and Data Latches for 32 Bytes  
Internal Control Timer
- **Fast Write Cycle Times**  
Maximum Page Write Cycle Time: 2 ms  
1 to 32 Byte Page Write Operation
- **Low Power Dissipation**  
80 mA Active Current  
100  $\mu$ A CMOS Standby Current
- **Direct Microprocessor Control**  
DATA Polling
- **High Reliability CMOS Technology**  
Endurance:  $10^4$  or  $10^5$  Cycles  
Data Retention: 10 years
- **Single 5 V  $\pm$  10% Supply**
- **CMOS and TTL Compatible Inputs and Outputs**
- **JEDEC Approved Byte-Wide Pinout**
- **Full Military, Commercial, and Industrial Temperature Ranges**

**64K (8K x 8)  
Paged  
CMOS  
E<sup>2</sup>PROM**

**Description**

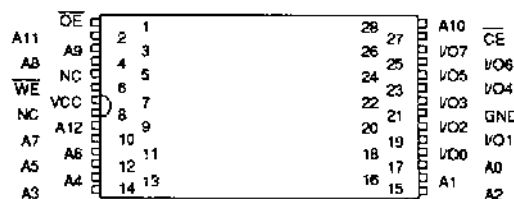
The AT28PC64 is a high-speed, low-power Electrically Erasable and Programmable Read Only Memory. Its 64K of memory is organized as 8,192 words by 8 bits. Manufactured with Atmel's advanced nonvolatile CMOS technology, the device offers access times to 150 ns with power dissipation of just 440 mW. When the device is deselected the standby current is less than 100  $\mu$ A.

The AT28PC64 is accessed like a Static RAM for the read or write cycles without the need for external components. The device contains a 32-byte page register to allow writing of up to 32 bytes simultaneously. During a write cycle, the addresses and 1 to 32 bytes of data are

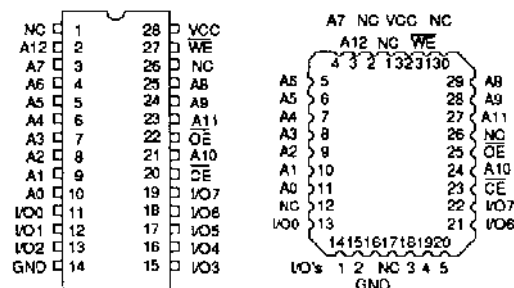
*(continued on next page)*

**Pin Configurations**

TSOP Top View



Pin Name	Function
A0 - A12	Addresses
CE	Chip Enable
OE	Output Enable
WE	Write Enable
I/O0 - I/O7	Data Inputs/Outputs
NC	No Connect



Note: PLCC package pins 1 and 17 are DON'T CONNECT.



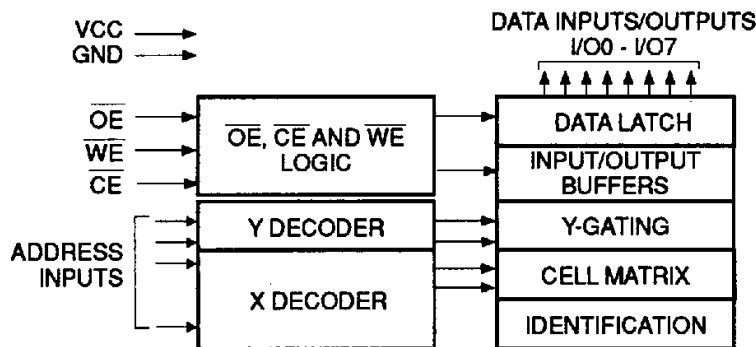


## Description (Continued)

internally latched, freeing the address and data bus for other operations. Following the initiation of a write cycle, the device will automatically write the latched data using an internal control timer. The end of a write cycle can be detected by  $\overline{\text{DATA}}$  polling of I/O7. Once the end of a write cycle has been detected a new access for a read or write can begin.

Atmel's 28PC64 has additional features to ensure high quality and manufacturability. The device utilizes internal error correction for extended endurance and improved data retention characteristics. The AT28PC64 also includes an extra 32 bytes of E<sup>2</sup>PROM for device identification or tracking.

## Block Diagram



## Absolute Maximum Ratings\*

Temperature Under Bias.....	-55°C to +125°C
Storage Temperature.....	-65°C to +150°C
All Input Voltages (including N.C. Pins) with Respect to Ground .....	-0.6 V to +6.25 V
All Output Voltages with Respect to Ground .....	-0.6 V to V <sub>CC</sub> +0.6 V
Voltage on $\overline{\text{OE}}$ and A9 with Respect to Ground .....	-0.6 V to +13.5 V

\*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## Device Operation

**READ:** The AT28PC64 is accessed like a Static RAM. When  $\overline{CE}$  and  $\overline{OE}$  are low and  $\overline{WE}$  is high, the data stored at the memory location determined by the address pins is asserted on the outputs. The outputs are put in the high impedance state when either  $\overline{CE}$  or  $\overline{OE}$  is high. This dual-line control gives designers flexibility in preventing bus contention in their system.

**BYTE WRITE:** A low pulse on the  $\overline{WE}$  or  $\overline{CE}$  input with  $\overline{CE}$  or  $\overline{WE}$  low (respectively) and  $\overline{OE}$  high initiates a write cycle. The address is latched on the falling edge of  $\overline{CE}$  or  $\overline{WE}$ , whichever occurs last. The data is latched by the first rising edge of  $\overline{CE}$  or  $\overline{WE}$ . Once a byte write has been started it will automatically time itself to completion.

**PAGE WRITE:** The page write operation of the AT28PC64 allows one to thirty-two bytes of data to be written into the device during a single internal programming period. A page write operation is initiated in the same manner as a byte write; the first byte written can then be followed by one to thirty-one additional bytes. Each successive byte must be written within 150  $\mu$ s (tBLC) of the previous byte. If the tBLC limit is exceeded the AT28PC64 will cease accepting data and commence the internal programming operation. All bytes during a page write operation must reside on the same page as defined by the state of the A5-A12 inputs. For each  $\overline{WE}$  high to low transition during the page write operation, A5 - A12 must be the same.

The A0 to A4 inputs are used to specify which bytes within the page are to be written. The bytes may be loaded in any order and may be altered within the same load period. Only bytes which are specified for writing will be written; unnecessary cycling of other bytes within the page does not occur.

**DATA POLLING:** The AT28PC64 features  $\overline{DATA}$  Polling to indicate the end of a write cycle. During a byte or page write cycle an attempted read of the last byte written will result in the complement of the written data to be presented on I/O7. Once

the write cycle has been completed, true data is valid on all outputs, and the next write cycle may begin.  $\overline{DATA}$  Polling may begin at anytime during the write cycle.

**TOGGLE BIT:** In addition to  $\overline{DATA}$  Polling the AT28PC64 provides another method for determining the end of a write cycle. During the write operation, successive attempts to read data from the device will result in I/O6 toggling between one and zero. Once the write has completed, I/O6 will stop toggling and valid data will be read. Reading the toggle bit may begin at any time during the write cycle.

**DATA PROTECTION:** If precautions are not taken, inadvertent writes to the AT28PC64 may occur during transitions of the host system power supply. Atmel has incorporated the following features that will protect the memory against inadvertent writes.

**HARDWARE PROTECTION:** Hardware features protect against inadvertent writes to the AT28PC64 in the following ways: (a) VCC sense - if VCC is below 3.8 V (typical) the write function is inhibited; (b) VCC power-on delay - once VCC has reached 3.8 V the device will automatically time out 5 ms (typical) before allowing a write; (c) write inhibit - holding any one of  $\overline{OE}$  low,  $\overline{CE}$  high or  $\overline{WE}$  high inhibits write cycles; (d) noise filter - pulses of less than 15 ns (typical) on the  $\overline{WE}$  or  $\overline{CE}$  inputs will not initiate a write cycle.

**CHIP CLEAR:** The contents of the entire memory of the AT28PC64 may be set to the high state (erased) by the use of the CHIP CLEAR operation. By setting  $\overline{CE}$  low and  $\overline{OE}$  to 12 volts, the chip is cleared when a 10 ms low pulse is applied to the  $\overline{WE}$  pin.

**DEVICE IDENTIFICATION:** An extra 32 bytes of E<sup>2</sup>PROM memory are available to the user for device identification. By raising A9 to 12 V  $\pm$  0.5 V and using address locations 1FE0H to 1FFFH the additional bytes may be written to or read from in the same manner as the regular memory array.

## Pin Capacitance (f = 1 MHz, T = 25°C) <sup>(1)</sup>

	Typ	Max	Units	Conditions
C <sub>IN</sub>	4	6	pF	V <sub>IN</sub> = 0 V
C <sub>OUT</sub>	8	12	pF	V <sub>OUT</sub> = 0 V

Note: 1. This parameter is characterized and is not 100% tested.





## D.C. and A.C. Operating Range

		AT28PC64-15	AT28PC64-20	AT28PC64-25
Operating Temperature (Case)	Com.	0°C - 70°C	0°C - 70°C	0°C - 70°C
	Ind.	-40°C - 85°C	-40°C - 85°C	-40°C - 85°C
	Mil.	-55°C - 125°C	-55°C - 125°C	-55°C - 125°C
Vcc Power Supply		5 V ± 10%	5 V ± 10%	5 V ± 10%

## Operating Modes

Mode	$\overline{CE}$	$\overline{OE}$	$\overline{WE}$	I/O
Read	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	DOUT
Write <sup>(2)</sup>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	DIN
Standby/Write Inhibit	V <sub>IH</sub>	X <sup>(1)</sup>	X	High Z
Write Inhibit	X	X	V <sub>IH</sub>	
Write Inhibit	X	V <sub>IL</sub>	X	
Output Disable	X	V <sub>IH</sub>	X	High Z
Chip Erase	V <sub>IL</sub>	V <sub>H</sub> <sup>(3)</sup>	V <sub>IL</sub>	High Z

Notes: 1. X can be V<sub>IL</sub> or V<sub>IH</sub>.

2. Refer to A.C. Programming Waveforms.

3. V<sub>H</sub> = 12.0 V ± 0.5 V.

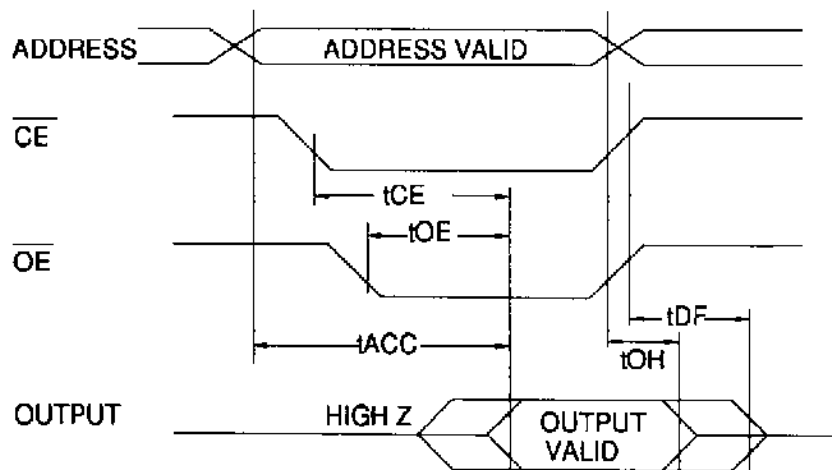
## D.C. Characteristics

Symbol	Parameter	Condition	Min	Max	Units
I <sub>LI</sub>	Input Load Current	V <sub>IN</sub> = 0 V to V <sub>CC</sub> + 1 V		10	μA
I <sub>LO</sub>	Output Leakage Current	V <sub>IO</sub> = 0 V to V <sub>CC</sub>		10	μA
I <sub>SB1</sub>	V <sub>CC</sub> Standby Current CMOS	$\overline{CE} = V_{CC} - 0.3 \text{ V to } V_{CC} + 1 \text{ V}$	Com., Ind.	100	μA
			Mil.	200	μA
I <sub>SB2</sub>	V <sub>CC</sub> Standby Current TTL	$\overline{CE} = 2.0 \text{ V to } V_{CC} + 1 \text{ V}$		3	mA
I <sub>CC</sub>	V <sub>CC</sub> Active Current	f = 5 MHz; I <sub>OUT</sub> = 0 mA		80	mA
V <sub>IL</sub>	Input Low Voltage			0.8	V
V <sub>IH</sub>	Input High Voltage		2.0		V
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.1 mA		.4	V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -400 μA	2.4		V

A.C. Characteristics <sup>(1)</sup>

Symbol	Parameter	AT28PC64-15		AT28PC64-20		AT28PC64-25		Units
		Min	Max	Min	Max	Min	Max	
t <sub>ACC</sub>	Address to Output Delay		150		200		250	ns
t <sub>CE</sub> <sup>(2)</sup>	$\overline{CE}$ to Output Delay		150		200		250	ns
t <sub>OE</sub> <sup>(3)</sup>	$\overline{OE}$ to Output Delay	0	70	0	80	0	100	ns
t <sub>DF</sub> <sup>(4,5)</sup>	$\overline{CE}$ or $\overline{OE}$ to Output Float	0	50	0	55	0	60	ns
t <sub>OH</sub>	Output Hold from $\overline{OE}$ , $\overline{CE}$ or Address, whichever occurred first	0		0		0		ns

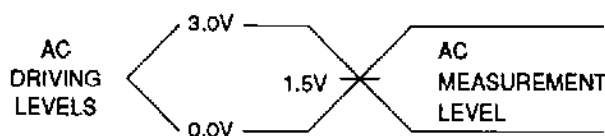
A.C. Read Waveforms



Notes:

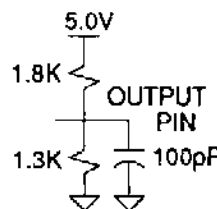
1. C<sub>L</sub> = 100 pF.
2.  $\overline{CE}$  may be delayed up to t<sub>ACC</sub> - t<sub>CE</sub> after the address transition without impact on t<sub>ACC</sub>.
3.  $\overline{OE}$  may be delayed up to t<sub>CE</sub> - t<sub>OE</sub> after the falling edge of  $\overline{CE}$  without impact on t<sub>CE</sub> or by t<sub>ACC</sub> - t<sub>OE</sub> after an address change without impact on t<sub>ACC</sub>.
4. t<sub>DF</sub> is specified from  $\overline{OE}$  or  $\overline{CE}$  whichever occurs first (C<sub>L</sub> = 5 pF).
5. This parameter is characterized and is not 100% tested.

Input Test Waveforms and Measurement Level



t<sub>R</sub>, t<sub>F</sub> < 5 ns

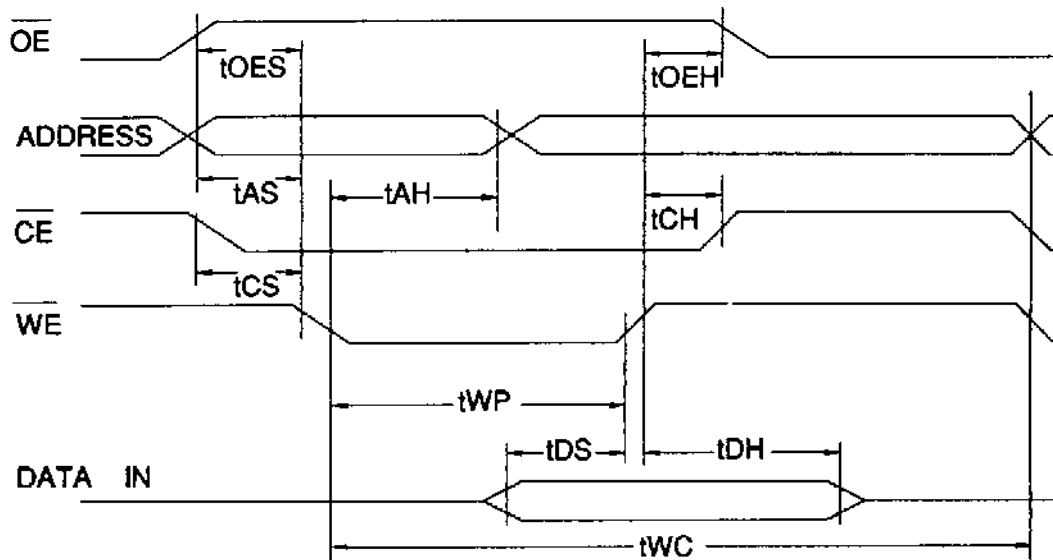
Output Test Load



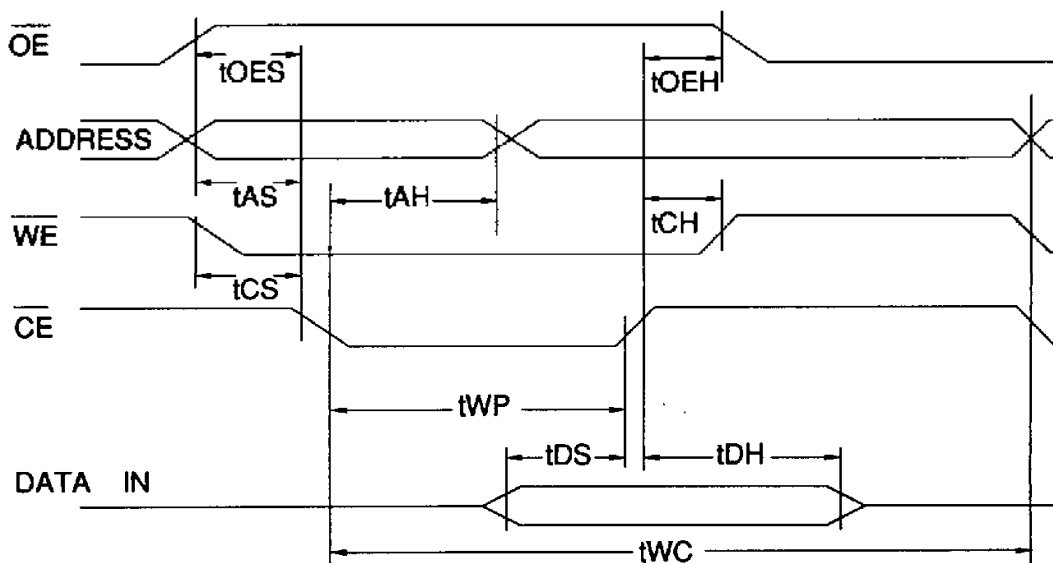
## A.C. Write Characteristics

Symbol	Parameter	Min	Typ	Max	Units
$t_{AS}, t_{OES}$	Address, $\overline{OE}$ Set-up Time	0			ns
$t_{AH}$	Address Hold Time	50			ns
$t_{CS}$	Chip Select Set-up Time	0			ns
$t_{CH}$	Chip Select Hold Time	0			ns
$t_{WP}$	Write Pulse Width ( $\overline{WE}$ or $\overline{CE}$ )	100		1000	ns
$t_{DS}$	Data Set-up Time	50			ns
$t_{DH}, t_{OEH}$	Data, $\overline{OE}$ Hold Time	0			ns
$t_{WC}$	Write Cycle Time		1.0	2.0	ms

### A.C. Write Waveforms- $\overline{WE}$ Controlled



### A.C. Write Waveforms- $\overline{CE}$ Controlled

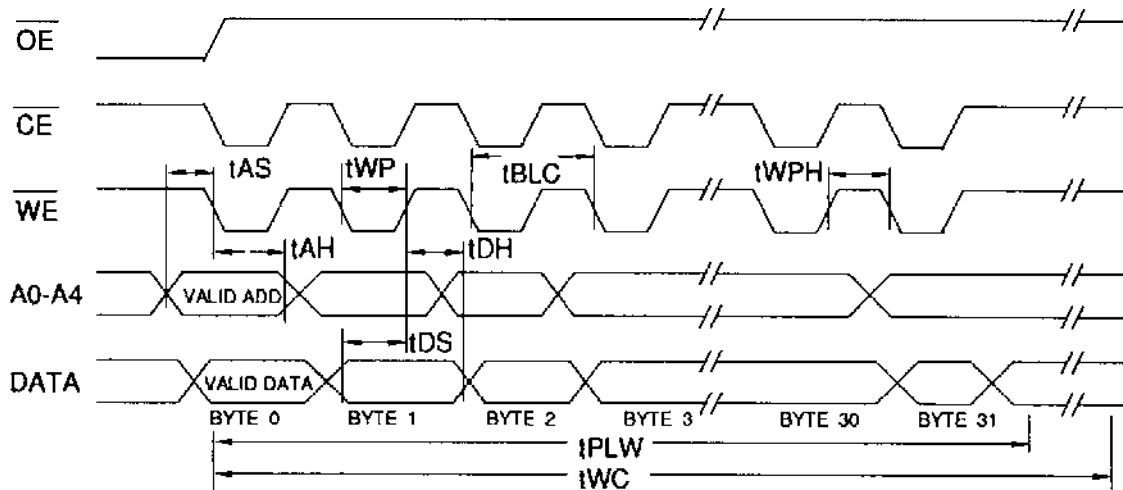


Page Mode Write Characteristics

Symbol	Parameter	Min	Typ	Max	Units
t <sub>WC</sub>	Write Cycle Time		1	2.0	ms
t <sub>AS</sub>	Address Set-up Time	0			ns
t <sub>AH</sub>	Address Hold Time	50			ns
t <sub>DS</sub>	Data Set-up Time	50			ns
t <sub>DH</sub>	Data Hold Time	0			ns
t <sub>WP</sub>	Write Pulse Width	100		1000	ns
t <sub>BLC</sub>	Byte Load Cycle Time	150			ns
t <sub>PLW</sub>	Page Load Width			150	μs
t <sub>WPH</sub>	Write Pulse Width High	50			ns

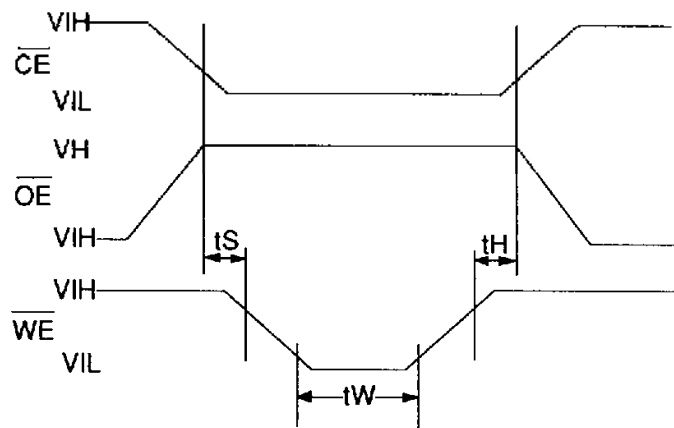
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Page Mode Write Waveforms



Notes: A5 through A12 must specify the same page address during each high to low transition of WE (or CE).  
 OE must be high only when WE and CE are both low.

Chip Erase Waveforms



t<sub>S</sub> = t<sub>H</sub> = 1 μsec (min.)  
 t<sub>W</sub> = 10 msec (min.)  
 V<sub>H</sub> = 12.0 V ± 0.5 V



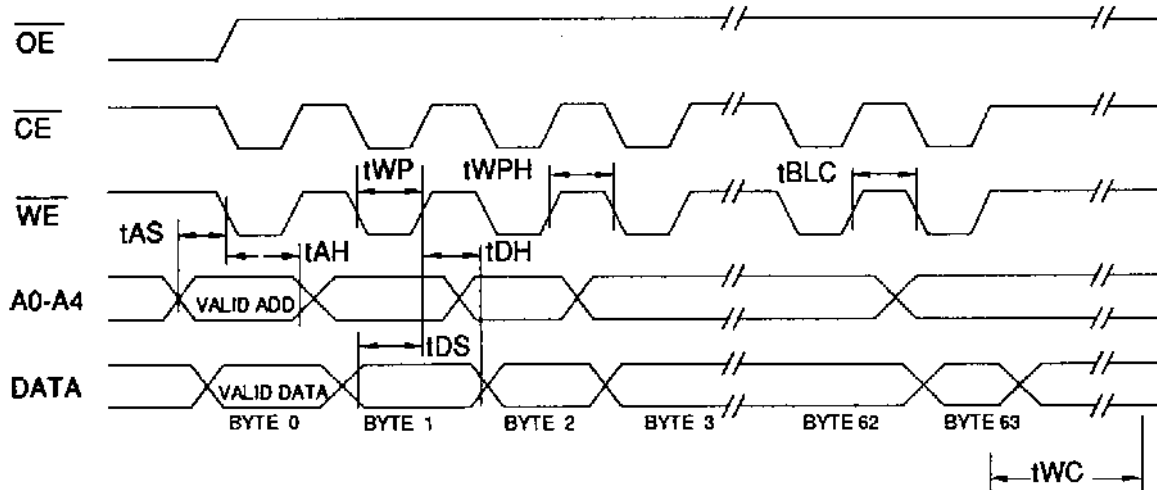


Note: Some systems require increased load cycle time, beyond that permitted by the AT28PC64. The following Page Mode Write Characteristics and Waveforms address this situation. Please reference Atmel part number AT28PC64-SL376 to specify this device.

### Page Mode Write Characteristics (AT28PC64-SL376)

Symbol	Parameter	Min	Typ	Max	Units
tWC	Write Cycle Time		1	2.0	ms
tAS	Address Set-up Time	0			ns
tAH	Address Hold Time	50			ns
tDS	Data Set-up Time	50			ns
tDH	Data Hold Time	0			ns
tWP	Write Pulse Width	100			ns
tBLC	Byte Load Cycle Time			150	μs
tWPH	Write Pulse Width High	50			ns

### Page Mode Write Waveforms (AT28PC64-SL376)



Notes: A5 through A12 must specify the same page address during each high to low transition of  $\overline{WE}$  (or  $\overline{CE}$ ).  $\overline{OE}$  must be high only when  $\overline{WE}$  and  $\overline{CE}$  are both low.



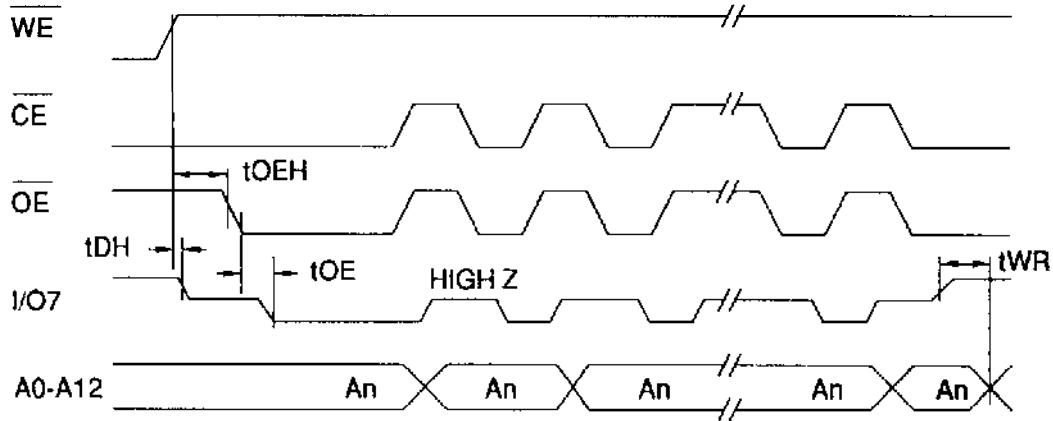
Data Polling Characteristics<sup>(1)</sup>

Symbol	Parameter	Min	Typ	Max	Units
t <sub>DH</sub>	Data Hold Time	0			ns
t <sub>OEH</sub>	$\overline{OE}$ Hold Time	0			ns
t <sub>OE</sub>	$\overline{OE}$ to Output Delay			50	ns
t <sub>WR</sub>	Write Recovery Time	0			ns

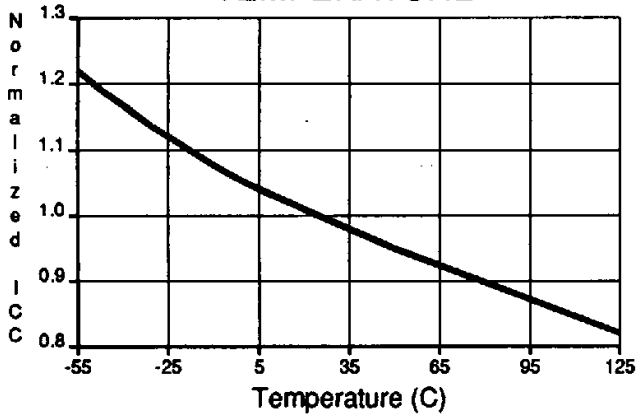
Note: 1. These parameters are characterized and not 100% tested.

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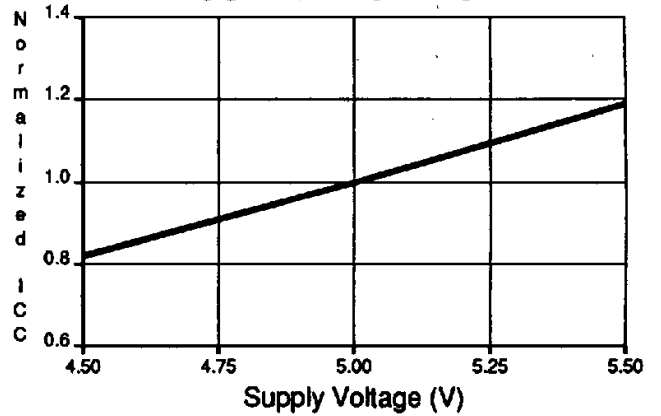
Data Polling Waveforms



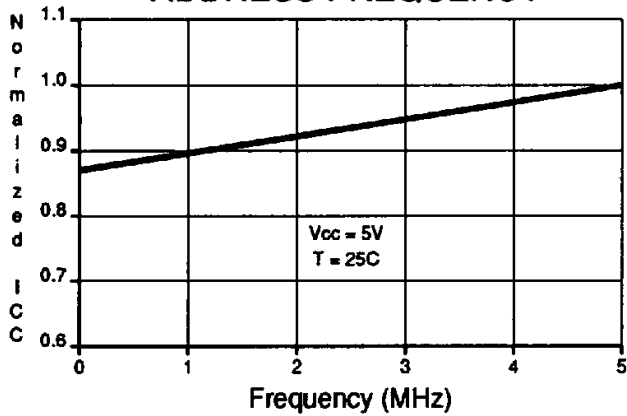
NORMALIZED SUPPLY CURRENT vs. TEMPERATURE



NORMALIZED SUPPLY CURRENT vs. SUPPLY VOLTAGE



NORMALIZED SUPPLY CURRENT vs. ADDRESS FREQUENCY



## Ordering Information

tACC (ns)	Icc (mA)		Ordering Code	Package	Operation Range
	Active	Standby			
150	80	0.1	AT28PC64(E)-15DC AT28PC64(E)-15JC AT28PC64(E)-15PC AT28PC64(E)-15TC	28D6 32J 28P6 28T	Commercial (0°C to 70°C)
			AT28PC64(E)-15DI AT28PC64(E)-15JI AT28PC64(E)-15PI AT28PC64(E)-15TI	28D6 32J 28P6 28T	Industrial (-40°C to 85°C)
150	80	0.2	AT28PC64(E)-15DM/883 AT28PC64(E)-15LM/883	28D6 32L	Military/883C Class B, Fully Compliant (-55°C to 125°C)
200	80	0.1	AT28PC64(E)-20DC AT28PC64(E)-20JC AT28PC64(E)-20PC	28D6 32J 28P6	Commercial (0°C to 70°C)
			AT28PC64(E)-20DI AT28PC64(E)-20JI AT28PC64(E)-20PI	28D6 32J 28P6	Industrial (-40°C to 85°C)
200	80	0.2	AT28PC64(E)-20DM/883 AT28PC64(E)-20LM/883	28D6 32L	Military/883C Class B, Fully Compliant (-55°C to 125°C)
250	80	0.1	AT28PC64(E)-25DC AT28PC64(E)-25JC AT28PC64(E)-25PC AT28PC64-W	28D6 32J 28P6 DIE	Commercial (0°C to 70°C)
			AT28PC64(E)-25DI AT28PC64(E)-25JI AT28PC64(E)-25PI	28D6 32J 28P6	Industrial (-40°C to 85°C)
250	80	0.2	AT28PC64(E)-25DM/883 AT28PC64(E)-25LM/883	28D6 32L	Military/883C Class B, Fully Compliant (-55°C to 125°C)
300 <sup>(1)</sup>	80	0.2	AT28PC64(E)-30DM/883 AT28PC64(E)-30LM/883	28D6 32L	Military/883 Class B, Fully Compliant (-55°C to 125°C)
350 <sup>(1)</sup>	80	0.2	AT28PC64(E)-35DM/883 AT28PC64(E)-35LM/883	28D6 32L	Military/883 Class B, Fully Compliant (-55°C to 125°C)

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## Ordering Information

t <sub>ACC</sub> (ns)	I <sub>CC</sub> (mA)		Ordering Code	Package	Operation Range
	Active	Standby			
200	80	0.2	5962-87514 09 XX 5962-87514 09 YX	28D6 32L	Military/883C Class B, Fully Compliant (-55°C to 125°C)
250	80	0.2	5962-87514 08 XX 5962-87514 08 YX	28D6 32L	Military/883C Class B, Fully Compliant (-55°C to 125°C)
300 <sup>(1)</sup>	80	0.2	5962-87514 07 XX 5962-87514 07 YX	28D6 32L	Military/883C Class B, Fully Compliant (-55°C to 125°C)
350 <sup>(1)</sup>	80	0.2	5962-87514 06 XX 5962-87514 06 YX	28D6 32L	Military/883C Class B, Fully Compliant (-55°C to 125°C)

Notes: 1. Electrical specifications for these speeds are defined in Standardized Military Drawing 5962-87514.

Package Type	
28D6	28 Lead, 0.600" Wide, Non-Windowed, Ceramic Dual Inline Package (Cerdip)
32J	32 Lead, Plastic J-Leaded Chip Carrier OTP (PLCC)
32L	32 Pad, Non-Windowed, Ceramic Leadless Chip Carrier OTP (LCC)
28P6	28 Lead, 0.600" Wide, Plastic Dual Inline Package OTP (PDIP)
28T	28 Lead, Plastic Thin Small Outline Package (TSOP)
W	Die
Options	
Blank	Standard Device: Endurance = 10K Write Cycles; Write Time = 2 ms
E	High Endurance Option: Endurance = 100K Write Cycles